

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)



[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)

IEEE Xplore®
RELEASE 1.8

Welcome
United States Patent and Trademark Office

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced
- CrossRef

Member Services

- Join IEEE
- Establish IEEE Web Account
- Access the IEEE Member Digital Library

IEEE Enterprise

- Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**

[Help](#)

- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.
Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

three <paragraph>
dimensional* and (judg* or
evaluat*) and (wafer or
substrate or semiconductor or



Start Search **Clear**

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:

Select publication types:

- IEEE Journals
- IEE Journals
- IEEE Conference proceedings
- IEE Conference proceedings
- IEEE Standards

Select years to search:

From year: to

Organize search results by:

Sort by:
In: order

List Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)

RELEASE 1.8

Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- [Home](#)
- [What Can I Access?](#)
- [Log-out](#)

Tables of Contents

- [Journals & Magazines](#)
- [Conference Proceedings](#)
- [Standards](#)

Search

- [By Author](#)
- [Basic](#)
- [Advanced](#)
- [CrossRef](#)

Member Services

- [Join IEEE](#)
- [Establish IEEE Web Account](#)
- [Access the IEEE Member Digital Library](#)

IEEE Enterprise

- [Access the IEEE Enterprise File Cabinet](#)

 [Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

